

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.  TI-14124D.5		SERIAL NO.  div. of 10/649,274	
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Lee D. Whetsel			
				FILING DATE October 20, 2003		GROUP <del>TBD</del> 2133	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
CB		EP 0,310,152	4/5/1989	Europe	G01	R31/28	X
		JP 01-038674 A	2/8/1989	Japan	G01R	31/28	X
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		JP 01-110274	4/26/1989	Japan	G01R31	28	X
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EXAMINER C. Brutt							
DATE CONSIDERED 4-21-05							
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